# onsemi

# **MOSFET** – Power, N-Channel 80 V, 1.27 m $\Omega$

# NVCR4LS1D3N08M7A

#### Features

- Typical  $R_{DS(on)} = 1.0 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$
- Typical  $Q_{g(tot)} = 172 \text{ nC}$  at  $V_{GS} = 10 \text{ V}$
- AEC-Q101 Qualified and PPAP Capable
- RoHS Compliant



#### **ORDERING INFORMATION**

Device	Package
NVCR4LS1D3N08M7A	Wafer Sawn on Foil

#### DIMENSION (µm)

Die Size	6604 x 3683
Die Size (Sawn)	$6584 \pm 30 \text{ x } 3663 \pm 30$
Source Attach Area	6399.3 x 3452.6
Gate Attach Area	343.1 x 477.5
Die Thickness	101.6 ±19.1

Gate and Source: AlSiCu Drain: Ti-NiV-Ag (back side of die) Passivation: Polyimide Wafer Diameter: 8 inch Wafer sawn on UV Tape Bad dice identified in inking Gross Die Counts: 1001

#### **RECOMMENDED STORAGE CONDITIONS**

Temperature	22 to 28°C
RH	40 to 66%

The Chip	is	100%	Probed	to	Meet	the	Conditions	and	Limits
Specified at 7	Γ <sub>J</sub> :	= 25°C.							

Symbol	Parameter	Condition	Min	Тур	Max	Unit
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D$ = 250 $\mu$ A, $V_{GS}$ = 0 V	80	-	-	V
I <sub>DSS</sub>	Drain to Source Leakage Current	$V_{DS}$ = 80 V, $V_{GS}$ = 0 V	-	-	1	μA
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS}$ = ±20 V, $V_{DS}$ = 0 V	-	-	±100	nA
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS}$ = $V_{DS}$ , $I_D$ = 250 $\mu$ A	2.0	-	4.0	V
*R <sub>DS(on)</sub>	Bare Die Drain to Source On Resistance	I <sub>D</sub> = 5 A, V <sub>GS</sub> = 10 V	-	1.0	1.27	mΩ
*V <sub>SD</sub>	Source to Drain Diode Voltage	$I_{SD}$ = 5 A, $V_{GS}$ = 0 V	-	-	1.2	V
E <sub>AS</sub>	Single Pulse Drain-to-Source Avalanche Energy	L = 0.3 mH, I <sub>AS</sub> = 70 A	735	-	-	mJ

\*Accurate R<sub>DS(on)</sub>, V<sub>SD</sub> test at die level are not feasible for this thin die as limited by the test contact precision attainable in a die form. The max R<sub>DS(on)</sub>, V<sub>SD</sub> specification are defined from the historical performance of the die in package but are not guaranteed by test in production. The die R<sub>DS(on)</sub> performance depends on the Source wire/ribbon bonding layout.

#### MOSFET MAXIMUM RATINGS in Reference to the FDBL86361-F085 electrical data in TOLL

(T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Ratings	Unit
V <sub>DSS</sub>	Drain to Source Voltage	80	V
V <sub>GS</sub>	Gate to Source Voltage	±20	V
I <sub>D</sub>	Continuous Drain Current $R_{\theta JC}$ (V <sub>GS</sub> = 10) (Note 1) T <sub>C</sub> = 25°C T <sub>C</sub> = 100°C	371 262	A
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)	819	mJ
PD	Power Dissipation $R_{\theta JC}$	429	W
	Derate Above 25°C	2.86	W/°C
TJ, T <sub>STG</sub>	Operating and Storage Temperature	–55 to +175	°C
$R_{\thetaJC}$	Thermal Resistance, Junction to Case	0.35	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance, Junction to Ambient (Note 3)	43	°C/W

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Current is limited by silicon.

2. Starting  $T_J = 25^{\circ}$ C, L = 0.4 mH,  $I_{AS} = 64$  A,  $V_{DD} = 40$  V during inductor charging and  $V_{DD} = 0$  V during time in avalanche. 3.  $R_{0JA}$  is the sum of the junction–to–case and case–to–ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>0JC</sub> is guaranteed by design, while R<sub>0JA</sub> is determined by the board design. The maximum rating presented here is based on mounting on a 1 in<sup>2</sup> pad of 2oz copper.

ELECTRICAL CHARACTERISTICS in Reference to the FDBL86361-F085 electrical data in TOLL

(T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test	Conditions	Min.	Тур.	Max.	Unit				
OFF CHARAC	OFF CHARACTERISTICS										
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_{D}$ = 250 $\mu$ A, $V_{GS}$ = 0 V		80	-	-	V				
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V	$T_J = 25^{\circ}C$	-	-	1	μΑ				
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS}$ = ±20 V		-	-	±100	nA				

#### **ON CHARACTERISTICS**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS}=V_{DS},\ I_{D}=250\ \mu A$		2.0	3.0	4.0	V
R <sub>DS(on)</sub>	Drain to Source on Resistance	$I_{\rm D} = 80  \rm A,$	$T_J = 25^{\circ}C$	-	1.1	1.4	mΩ
		V <sub>GS</sub> = 10 V	T <sub>J</sub> = 175°C (Note 4)	-	2.4	3.1	mΩ

#### DYNAMIC CHARACTERISTICS

C <sub>iss</sub>	Input Capacitance	$V_{DS}$ = 40 V, $V_{GS}$ = 0 V, f = 1 MHz	-	12800	-	pF
C <sub>oss</sub>	Output Capacitance		_	1925	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	139	-	pF
Rg	Gate Resistance	f = 1 MHz	-	2.7	-	Ω
Q <sub>g(ToT)</sub>	Total Gate Charge	$V_{GS}$ = 0 to 10 V, $V_{DD}$ = 64 V, $I_{D}$ = 80 A	-	172	-	nC
Q <sub>g(th)</sub>	Threshold Gate Charge	$V_{GS}$ = 0 to 2 V, $V_{DD}$ = 64 V, $I_{D}$ = 80 A	-	23	-	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DD} = 64 \text{ V}, \text{ I}_{D} = 80 \text{ A}$	-	51	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		-	34	-	nC

#### SWITCHING CHARACTERISTICS

t <sub>d(on)</sub>	Turn-On Delay	$V_{DD} = 40 \text{ V}, \text{ I}_{D} = 80 \text{ A},$	-	42	-	ns
tr	Rise Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$	-	73	-	ns
t <sub>d(off)</sub>	Turn-Off Delay		-	87	-	ns
t <sub>f</sub>	Fall Time		-	48	-	ns

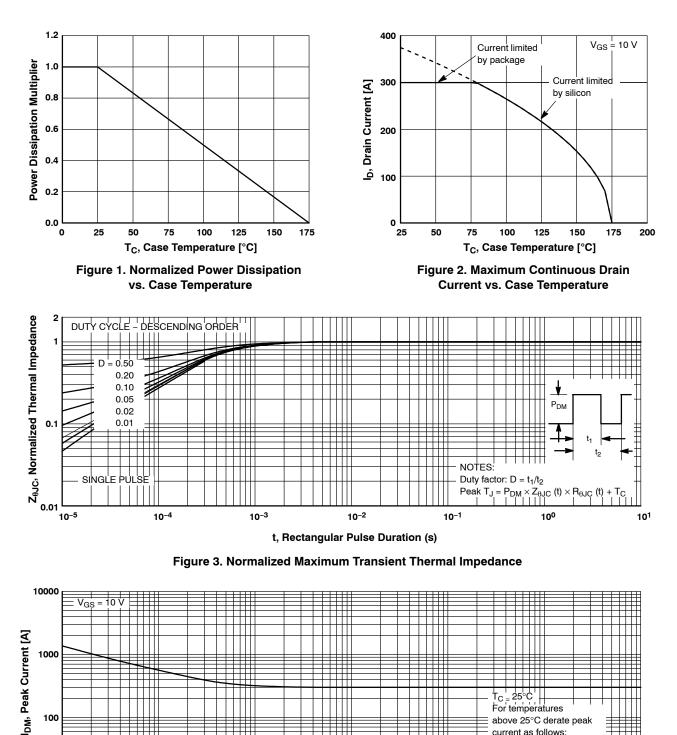
ELECTRICAL CHARACTERISTICS in Reference to the FDBL86361-F085 electrical data in TOLL

(T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit			
DRAIN-SOUR	DRAIN-SOURCE DIODE CHARACTERISTIC								
V <sub>SD</sub>	Source to Drain Diode Voltage	I <sub>SD</sub> = 80 A, V <sub>GS</sub> = 0 V	_	-	1.25	V			
		$I_{SD}$ = 40 A, $V_{GS}$ = 0 V	-	1	1.2	V			
t <sub>rr</sub>	Reverse Recovery Time	$I_{F} = 80 \text{ A}, \text{ dI}_{SD}/\text{dt} = 100 \text{ A}/\mu\text{s},$	-	117	-	ns			
Q <sub>rr</sub>	Reverse Recovery Charge	$V_{DD} = 64 \text{ V}$	_	205	_	nC			

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. The maximum value is specified by design at  $T_J = 175^{\circ}$ C. Product is not tested to this condition in production.

#### **TYPICAL CHARACTERISTICS**





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10<sup>-2</sup>

t, Rectangular Pulse Duration (s) Figure 4. Peak Current Capability

10<sup>-1</sup>

 $T_{C} = 25^{\circ}C$ For temperatures

above 25°C derate peak

175 – T<sub>C</sub>

150

10<sup>1</sup>

10<sup>0</sup>

current as follows:

1,2

10<sup>-3</sup>

100

10 10-5

10-4

#### TYPICAL CHARACTERISTICS (CONTINUED)

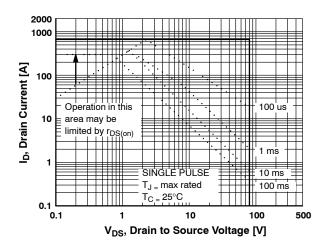


Figure 5. Forward Bias Safe Operating Area

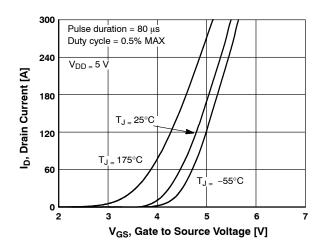
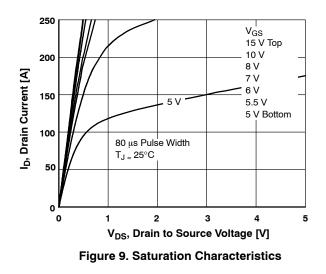


Figure 7. Transfer Characteristics



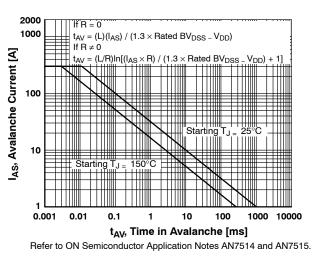
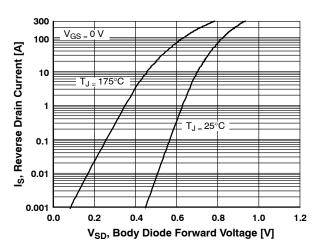
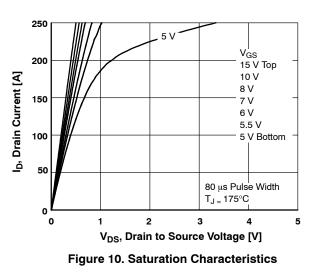


Figure 6. Unclamped Inductive Switching Capability







#### **TYPICAL CHARACTERISTICS (CONTINUED)**

Pulse duration = 80 µs

Duty cycle = 0.5% MAX

 $I_{D} = 80$  A

 $V_{GS} = 10 V$ 

120

120

V<sub>D</sub>D \_ 48 V

140

160

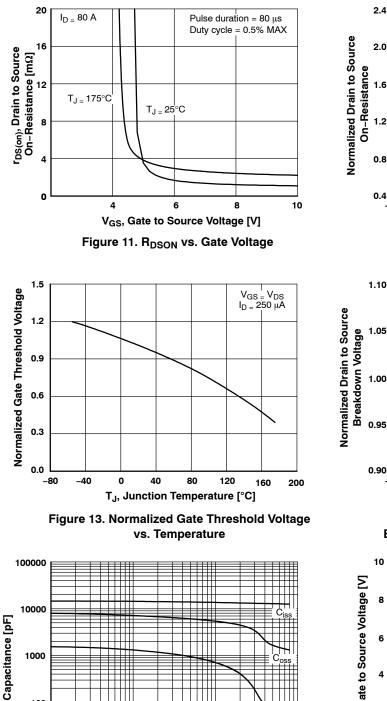
180

160

200

160

200



10

Figure 15. Capacitance vs. Drain to Source

Voltage

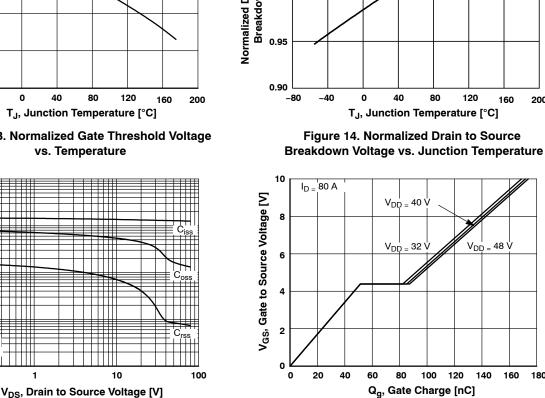
1

100

10

0.1

f = 1 MHz V<sub>GS =</sub> 0 V



-80

-40

 $I_D = 5 mA$ 

0

40

80

T<sub>J</sub>, Junction Temperature [°C]

Figure 12. Normalized R<sub>DSON</sub> vs. Junction Temperature



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